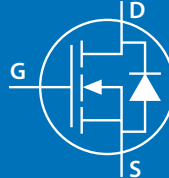


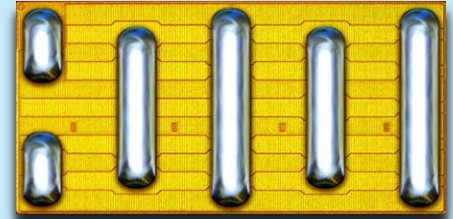
EPC2059 – Enhancement Mode Power Transistor

 $V_{DS}, 170\text{ V}$
 $R_{DS(on)}, 9\text{ m}\Omega$
 $I_D, 24\text{ A}$


Revised October 28, 2020

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Questions:
Ask a GaN
Expert



Die Size: 2.8 x 1.4 mm

EPC2059 eGaN® FETs are supplied only in passivated die form with solder bars.

Applications

- DC-DC Converters
- Sync rectification for AC/DC & DC-DC
- USB-C PD quick chargers and adaptors
- BLDC motor drives
- Lidar
- Class-D audio

Benefits

- Ultra high efficiency
- No reverse recovery
- Ultra low Q_G
- Small footprint

Scan QR code or click link below for more information including reliability reports, device models, demo boards!


<https://l.ead.me/EPC2059>

Maximum Ratings

PARAMETER	VALUE	UNIT
V_{DS} Drain-to-Source Voltage (Continuous)	170	V
I_D	Continuous ($T_A = 25^\circ\text{C}$)	24
	Pulsed (25°C , $T_{PULSE} = 300\text{ }\mu\text{s}$)	102
V_{GS}	Gate-to-Source Voltage	6
	Gate-to-Source Voltage	-4
T_J Operating Temperature	-40 to 150	$^\circ\text{C}$
T_{STG} Storage Temperature	-40 to 150	

Thermal Characteristics

PARAMETER	TYP	UNIT
$R_{\theta JC}$ Thermal Resistance, Junction-to-Case	0.9	$^\circ\text{C/W}$
$R_{\theta JB}$ Thermal Resistance, Junction-to-Board	3	
$R_{\theta JA}$ Thermal Resistance, Junction-to-Ambient (Note 1)	63	

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV_{DSS} Drain-to-Source Voltage	$V_{GS} = 0\text{ V}$, $I_D = 0.15\text{ mA}$	170			V
I_{DSS} Drain-Source Leakage	$V_{GS} = 0\text{ V}$, $V_{DS} = 136\text{ V}$		0.03	0.1	mA
I_{GSS}	Gate-to-Source Forward Leakage		0.01	2.4	
	Gate-to-Source Forward Leakage [#]	$V_{GS} = 5\text{ V}$, $T_J = 125^\circ\text{C}$	0.13	5.5	
	Gate-to-Source Reverse Leakage	$V_{GS} = -4\text{ V}$	0.03	0.2	
$V_{GS(TH)}$ Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 3\text{ mA}$	0.7	1	2.5	V
$R_{DS(on)}$ Drain-Source On Resistance	$V_{GS} = 5\text{ V}$, $I_D = 10\text{ A}$		6.8	9	m Ω
V_{SD} Source-Drain Forward Voltage [#]	$I_S = 0.5\text{ A}$, $V_{GS} = 0\text{ V}$		1.6		V

[#] Defined by design. Not subject to production test.

Dynamic Characteristics[#] ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C_{ISS}	Input Capacitance	$V_{DS} = 85\text{ V}, V_{GS} = 0\text{ V}$		633	836	pF
C_{RSS}	Reverse Transfer Capacitance			1.6		
C_{OSS}	Output Capacitance			267	401	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }85\text{ V}, V_{GS} = 0\text{ V}$		332		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			414		
R_G	Gate Resistance			0.5		Ω
Q_G	Total Gate Charge	$V_{DS} = 85\text{ V}, V_{GS} = 5\text{ V}, I_D = 10\text{ A}$		5.7	7.4	nC
Q_{GS}	Gate-to-Source Charge	$V_{DS} = 85\text{ V}, I_D = 10\text{ A}$		1.3		
Q_{GD}	Gate-to-Drain Charge			0.9		
$Q_{G(TH)}$	Gate Charge at Threshold			1.0		
Q_{OSS}	Output Charge	$V_{DS} = 85\text{ V}, V_{GS} = 0\text{ V}$		35	53	
Q_{RR}	Source-Drain Recovery Charge			0		

[#] Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

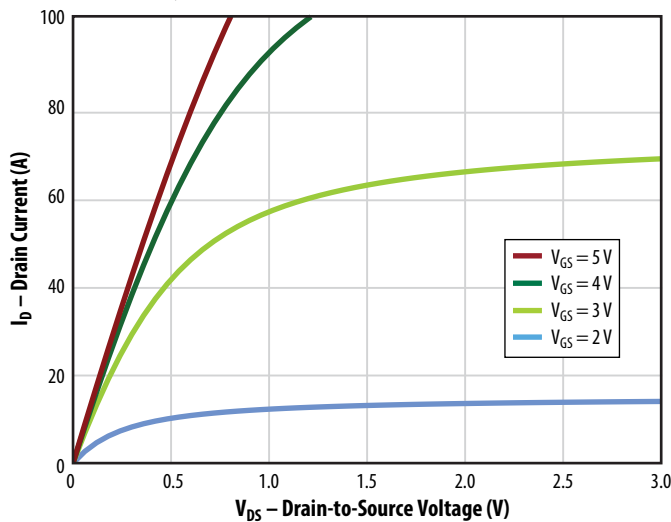
Figure 1: Typical Output Characteristics at 25°C 

Figure 2: Typical Transfer Characteristics

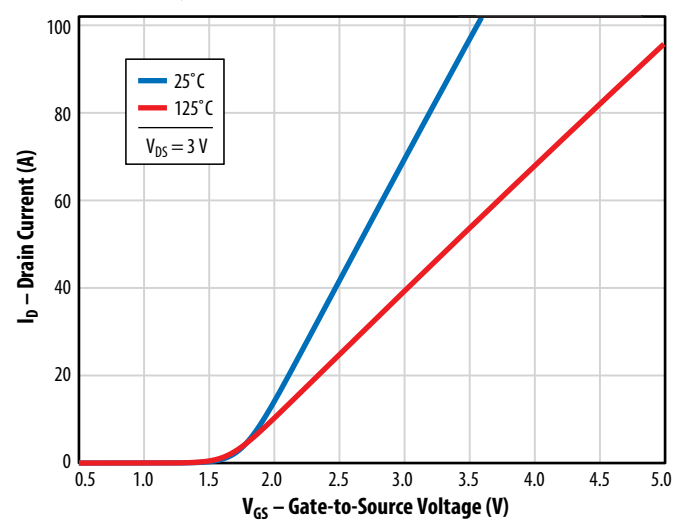
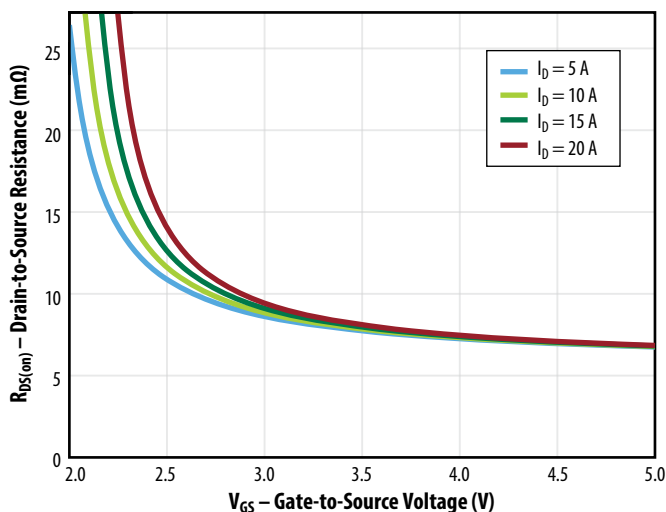
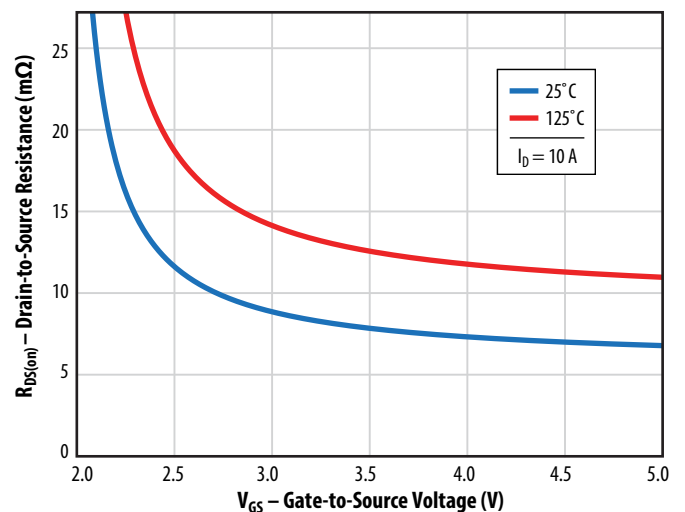
Figure 3: Typical $R_{DS(on)}$ vs. V_{GS} for Various Drain CurrentsFigure 4: Typical $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

Figure 5a: Typical Capacitance (Linear Scale)

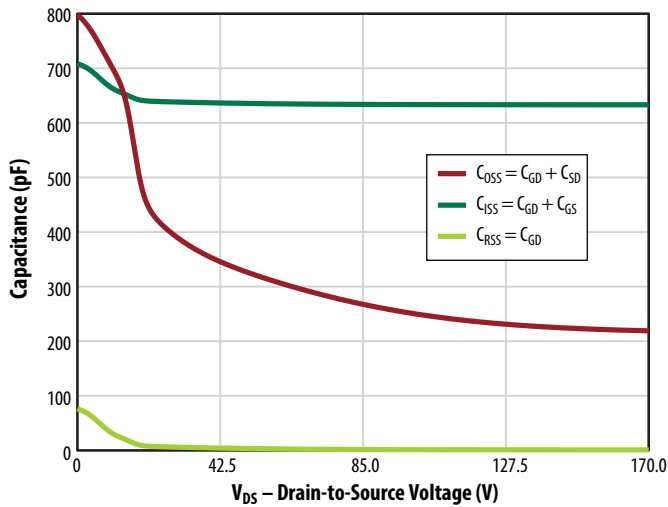


Figure 5b: Typical Capacitance (Log Scale)

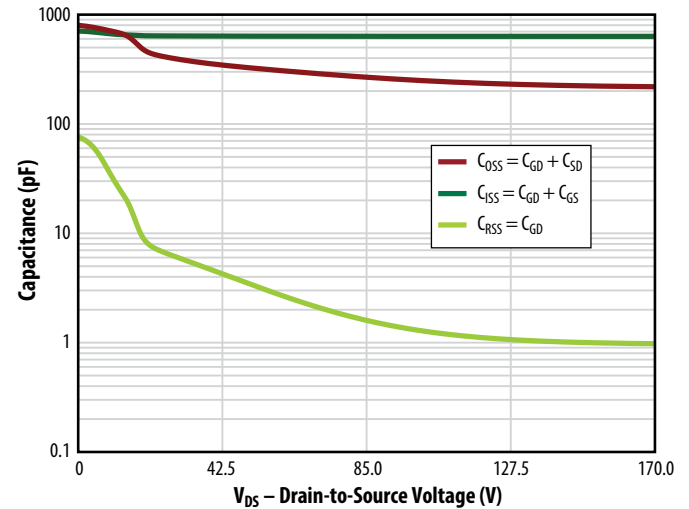
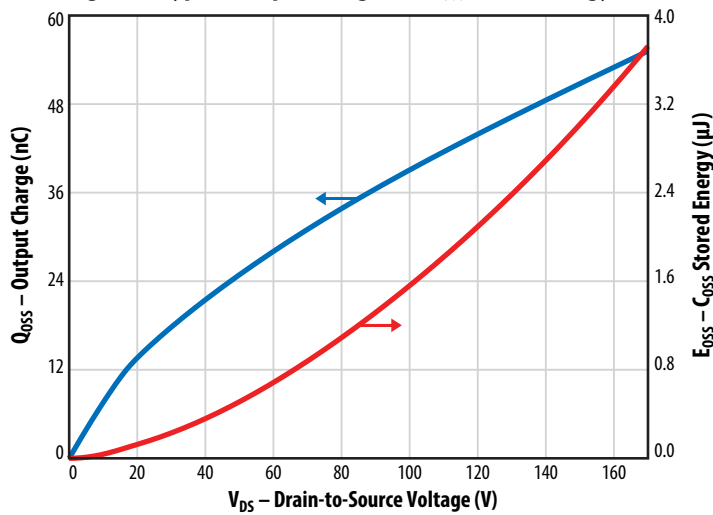
Figure 6: Typical Output Charge and C_{OSS} Stored Energy

Figure 7: Typical Gate Charge

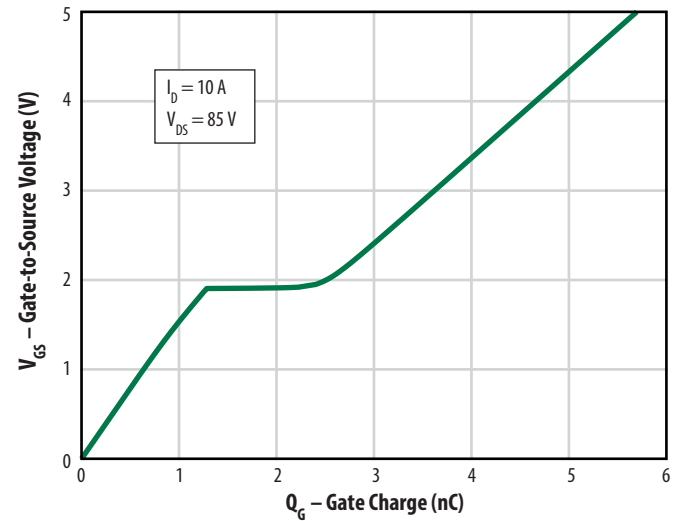


Figure 8: Typical Reverse Drain-Source Characteristics

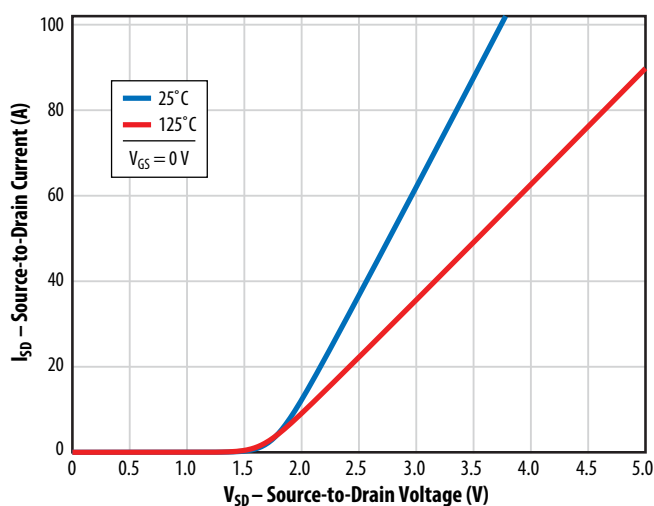
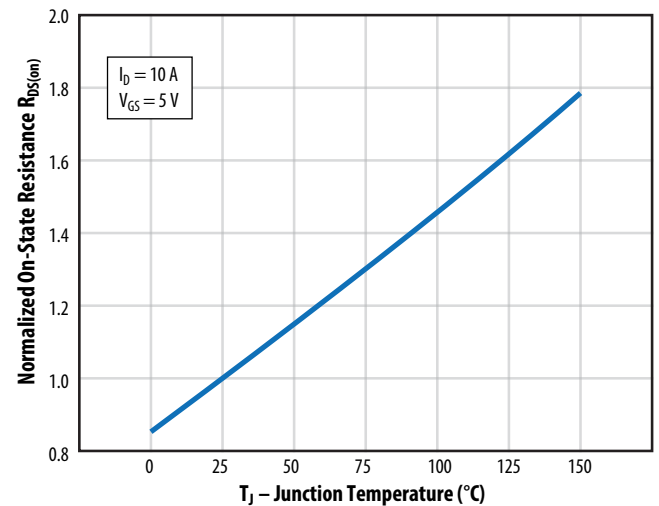


Figure 9: Typical Normalized On-State Resistance vs. Temp.



Note: Negative gate drive voltage increases the reverse drain-source voltage.
EPC recommends 0 V for OFF.

Figure 10: Typical Normalized Threshold Voltage vs. Temp.

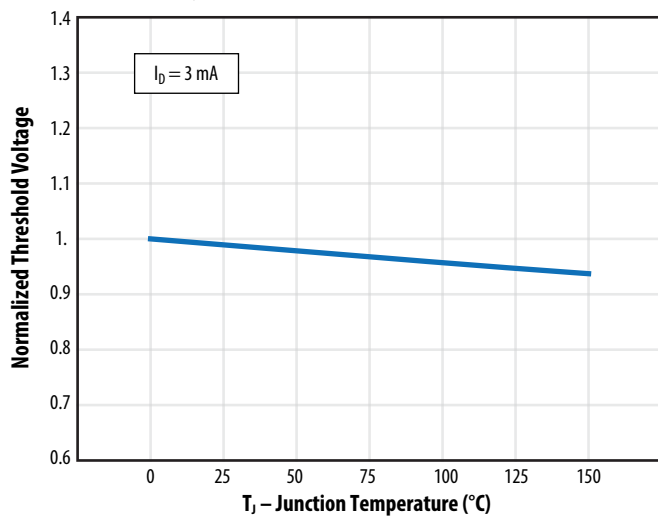


Figure 11: Safe Operating Area

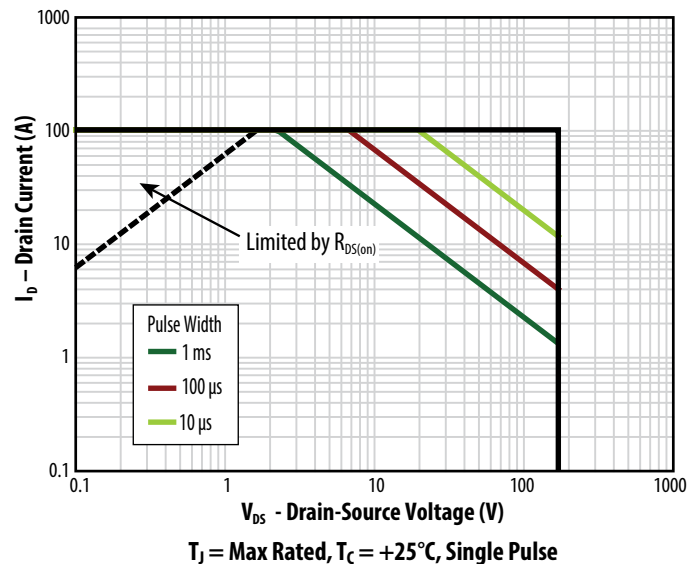
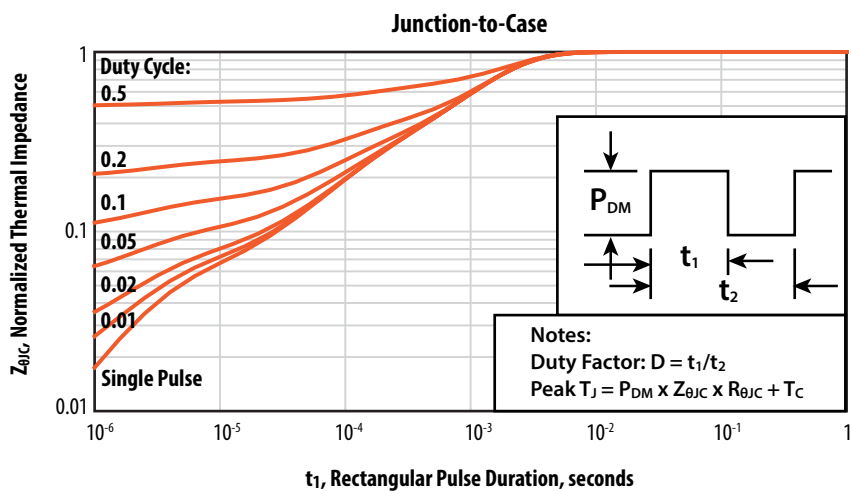
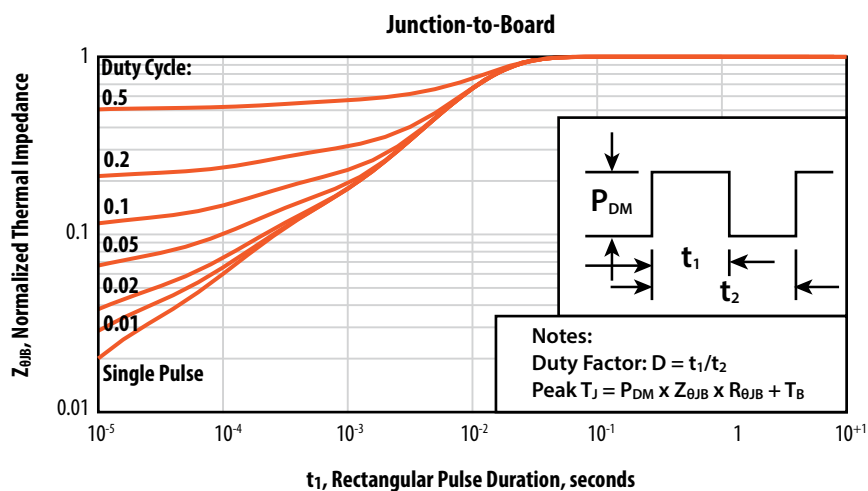


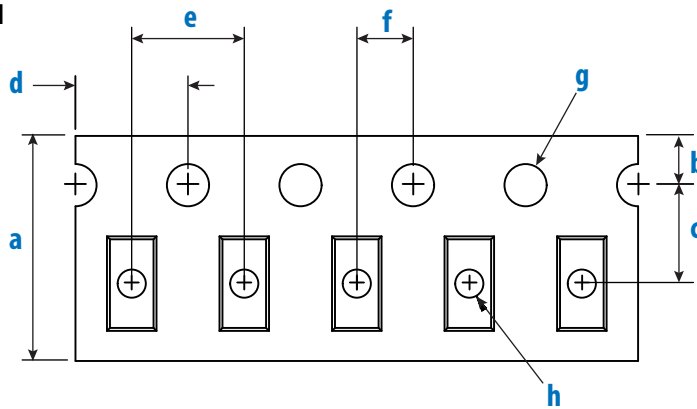
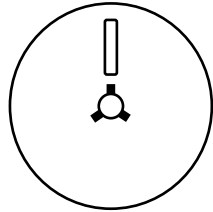
Figure 12: Typical Transient Thermal Response Curves



TAPE AND REEL CONFIGURATION

4 mm pitch, 8 mm wide tape on 7" reel

7" inch reel



Loaded Tape Feed Direction →



Die orientation dot
Gate solder bar is under this corner

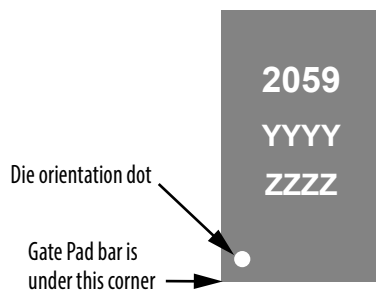
Die is placed into pocket
solder bar side down
(face side down)

EPC2059 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (Note 2)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60
h	1.00	0.95	1.05

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

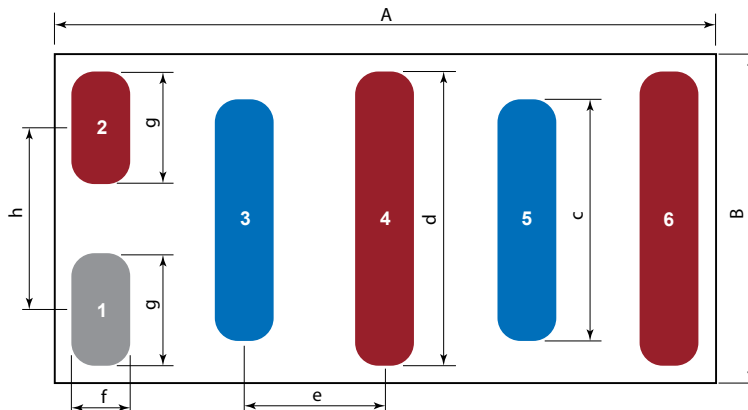
DIE MARKINGS



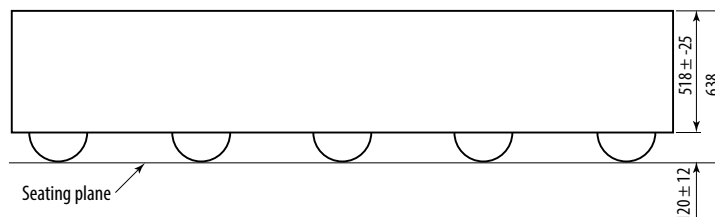
Part Number	Laser Markings		
	Part # Marking Line 1	Lot _Date Code Marking Line 2	Lot _Date Code Marking Line 3
EPC2059	2059	YYYY	ZZZZ

DIE OUTLINE

Solder Bump View



Side View

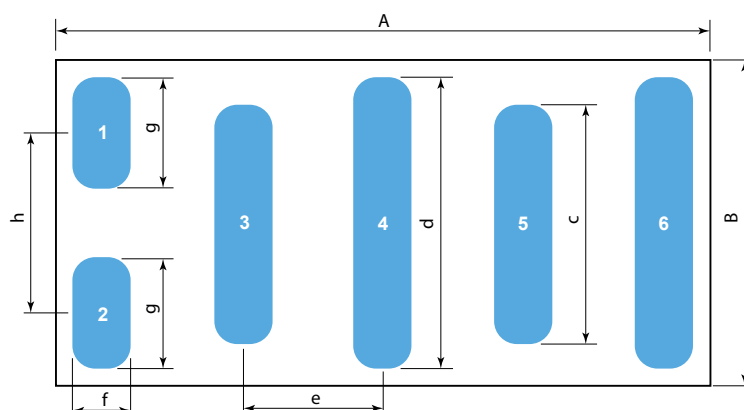


DIM	Micrometers		
	MIN	Nominal	MAX
A	2770	2800	2830
B	1370	1400	1430
c		1010	
d		1250	
e		600	
f		250	
g		475	
h		775	

Pad 1 is Gate;
Pads 2, 4, 6 are Source;
Pads 3, 5 are Drain

RECOMMENDED LAND PATTERN

(units in μm)



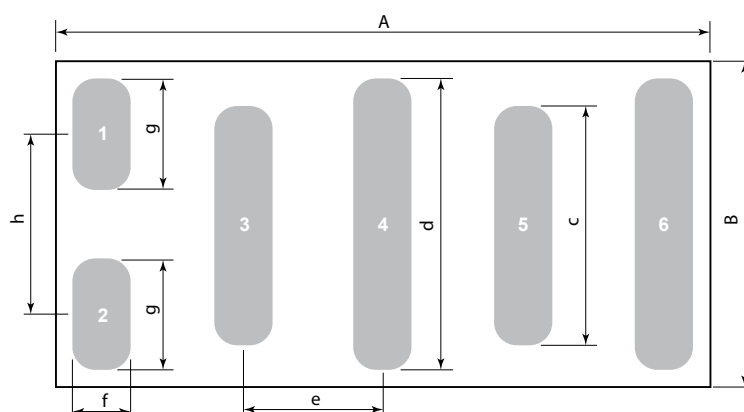
Land pattern is solder mask defined.

Pad 1 is Gate;
Pads 2, 4, 6
are Source;
Pads 3, 5 are Drain

DIM	Nominal
A	2800
B	1400
c	1010
d	1250
e	600
f	250
g	475
h	775

RECOMMENDED STENCIL DRAWING

(units in μm)



DIM	Nominal
A	2800
B	1400
c	1010
d	1250
e	600
f	250
g	475
h	775

Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, openings per drawing.

The corner has a radius of R60.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Split stencil design can be provided upon request, but EPC has tested this stencil design and not found any scooping issues.

Additional assembly resources available at <https://epc-co.com/epc/design-support>

Efficient Power Conversion Corporation (EPC) reserves the right to make changes without further notice to any products herein to improve reliability, function or design. EPC does not assume any liability arising out of the application or use of any product or circuit described herein; neither does it convey any license under its patent rights, nor the rights of others.

eGaN® is a registered trademark of Efficient Power Conversion Corporation.

EPC Patent Listing: <https://epc-co.com/about-epc/patents>

Information subject to change without notice.